## 2SB1438

## Silicon PNP epitaxial planar type

### For low-frequency power amplification

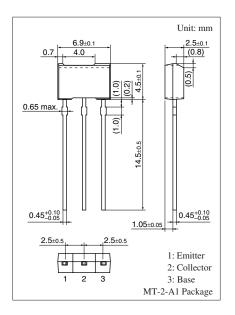
#### ■ Features

- Low collector-emitter saturation voltage V<sub>CE(sat)</sub>
- ullet Large collector-emitter voltage (Base open)  $V_{CEO}$
- Allowing supply with the radial taping

## ■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit			
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	-100	V			
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	-100	V			
Emitter-base voltage (Collector open)	$V_{EBO}$	-5	V			
Collector current	$I_C$	-2	A			
Peak collector current	$I_{CP}$	-3	A			
Collector power dissipation *	$P_{C}$	1	W			
Junction temperature	$T_j$	150	°C			
Storage temperature	T <sub>stg</sub>	-55 to +150	°C			

Note) \*: Print circuit board: Copper foil area of 1 cm<sup>2</sup> or more, and the board thickness of 1.7 mm for the collector portion



### ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

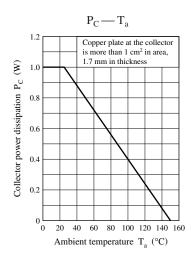
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	$I_C = -10 \mu A, I_E = 0$	-100			V
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_C = -1 \text{ mA}, I_B = 0$	-100			V
Emitter-base voltage (Collector open)	$V_{EBO}$	$I_E = -10 \ \mu A, \ I_C = 0$	-5			V
Collector-base cutoff current (Emitter open)	$I_{CBO}$	$V_{CB} = -50 \text{ V}, I_E = 0$			- 0.1	μΑ
Forward current transfer ratio	h <sub>FE1</sub> *2	$V_{CE} = -2 \text{ V}, I_{C} = -200 \text{ mA}$	120		340	
	h <sub>FE2</sub> *1	$V_{CE} = -2 \text{ V}, I_{C} = -1 \text{ A}$	60			
Collector-emitter saturation voltage *1	V <sub>CE(sat)</sub>	$I_C = -1 \text{ A}, I_B = -50 \text{ mA}$		- 0.17	- 0.30	V
Base-emitter saturation voltage *1	V <sub>BE(sat)</sub>	$I_C = -1 \text{ A}, I_B = -50 \text{ mA}$		- 0.85	-1.20	V
Transition frequency	$f_T$	$V_{CB} = -10 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$		90		MHz
Collector output capacitance	C <sub>ob</sub>	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		70	90	pF
(Common base, input open circuited)						

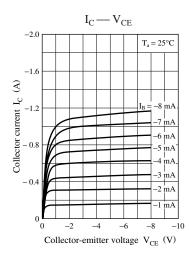
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

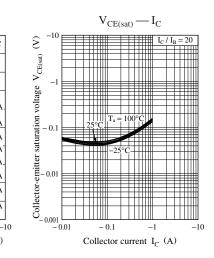
#### 2. \*1: Pulse measurement

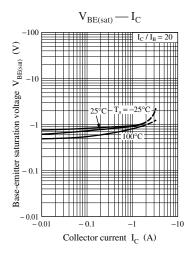
#### \*2: Rank classification

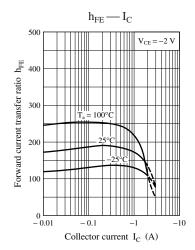
Rank	Р	Q
$h_{\rm FE1}$	120 to 240	170 to 340



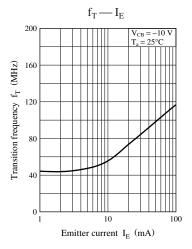


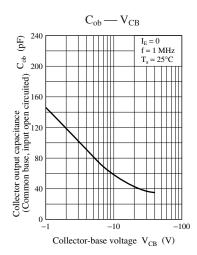






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